

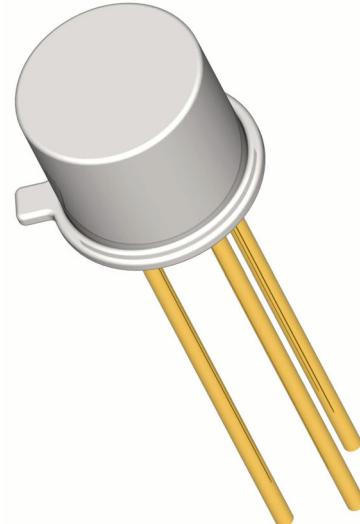
Description

Semicoa Semiconductors offers:

- Screening and processing per MIL-PRF-19500 Appendix E
- JAN level (2N930J)
- JANTX level (2N930JX)
- JANTXV level (2N930JV)
- QCI to the applicable level
- 100% die visual inspection per MIL-STD-750 method 2072 for JANTXV
- Radiation testing (total dose) upon request

Applications

- General purpose
- Low power
- NPN silicon transistor



Features

- Hermetically sealed TO-18 metal can
- Also available in chip configuration
- Chip geometry 0307
- Reference document: MIL-PRF-19500/253

Benefits

- Qualification Levels: JAN, JANTX, and JANTXV
- Radiation testing available

Absolute Maximum Ratings		$T_c = 25^\circ\text{C}$ unless otherwise specified	
Parameter	Symbol	Rating	Unit
Collector-Emitter Voltage	V_{CEO}	45	Volts
Collector-Base Voltage	V_{CBO}	60	Volts
Emitter-Base Voltage	V_{EBO}	6	Volts
Collector Current, Continuous	I_C	30	mA
Power Dissipation, $T_A = 25^\circ\text{C}$ Derate linearly above 25°C	P_T	360 2.06	mW mW/ $^\circ\text{C}$
Thermal Resistance	R_{QJA}	485	$^\circ\text{C}/\text{W}$
Operating Junction Temperature	T_J	-65 to +200	$^\circ\text{C}$
Storage Temperature	T_{STG}	-65 to +200	$^\circ\text{C}$

ELECTRICAL CHARACTERISTICS

characteristics specified at $T_A = 25^\circ\text{C}$

Off Characteristics

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Collector-Emitter Breakdown Voltage	$V_{(\text{BR})\text{CEO}}$	$I_C = 10 \text{ mA}$	45			Volts
Collector-Base Cutoff Current	$I_{\text{CBO}1}$ $I_{\text{CBO}2}$	$V_{\text{CB}} = 60 \text{ Volts}$ $V_{\text{CB}} = 45 \text{ Volts}$			10 10	μA nA
Collector-Emitter Cutoff Current	I_{CEO}	$V_{\text{CE}} = 5 \text{ Volts}$			2	nA
Collector-Emitter Cutoff Current	$I_{\text{CES}1}$ $I_{\text{CES}2}$	$V_{\text{CE}} = 45 \text{ Volts}$ $V_{\text{CE}} = 45 \text{ Volts}, T_A = 150^\circ\text{C}$			2 10	nA μA
Emitter-Base Cutoff Current	$I_{\text{EBO}1}$ $I_{\text{EBO}2}$	$V_{\text{EB}} = 6 \text{ Volts}$ $V_{\text{EB}} = 5 \text{ Volts}$			10 5	μA nA

On Characteristics

Pulse Test: Pulse Width = 300 μs , Duty Cycle $\leq 2.0\%$

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
DC Current Gain	$h_{\text{FE}1}$ $h_{\text{FE}2}$ $h_{\text{FE}3}$ $h_{\text{FE}4}$	$I_C = 10 \mu\text{A}, V_{\text{CE}} = 5 \text{ Volts}$ $I_C = 500 \mu\text{A}, V_{\text{CE}} = 5 \text{ Volts}$ $I_C = 10 \text{ mA}, V_{\text{CE}} = 5 \text{ Volts}$ $I_C = 10 \mu\text{A}, V_{\text{CE}} = 5 \text{ Volts}$ $T_A = -55^\circ\text{C}$	100 150 20		300 600	
Base-Emitter Saturation Voltage	$V_{\text{BEsat}1}$	$I_C = 10 \text{ mA}, I_B = 0.5 \text{ mA}$	0.6		1	Volts
Collector-Emitter Saturation Voltage	$V_{\text{CESat}1}$	$I_C = 10 \text{ mA}, I_B = 0.5 \text{ mA}$			1	Volts

Dynamic Characteristics

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Magnitude – Common Emitter, Short Circuit Forward Current Transfer Ratio	$ h_{\text{FE}} $	$V_{\text{CE}} = 5 \text{ Volts}, I_C = 500 \mu\text{A}$, $f = 30 \text{ MHz}$	1.5		6	
Small Signal Short Circuit Forward Current Transfer Ratio	h_{FE}	$V_{\text{CE}} = 5 \text{ Volts}, I_C = 1 \text{ mA}$, $f = 1 \text{ kHz}$	150		600	
Open Circuit Output Capacitance	C_{OBO}	$V_{\text{CB}} = 5 \text{ Volts}, I_E = 0 \text{ mA}$, $100 \text{ kHz} < f < 1 \text{ MHz}$			8	pF
Noise Figure	NF_1 NF_2 NF_3	$V_{\text{CE}} = 5 \text{ Volts}, I_C = 10 \mu\text{A}$, $R_g = 10 \text{ k}\Omega$, $f = 100 \text{ Hz}$ $f = 1 \text{ kHz}$ $f = 10 \text{ kHz}$			5 3 3	dB
Short Circuit Input Impedance	h_{ie}	$V_{\text{CB}} = 5 \text{ V}, I_C = 1 \text{ mA}, f = 1 \text{ kHz}$	25		32	Ω
Open Circuit Output Admittance	h_{oe}	$V_{\text{CB}} = 5 \text{ V}, I_C = 1 \text{ mA}, f = 1 \text{ kHz}$			1	mho
Open Circuit reverse Voltage Transfer Ratio	h_{re}	$V_{\text{CB}} = 5 \text{ V}, I_C = 1 \text{ mA}, f = 1 \text{ kHz}$			6×10^{-4}	